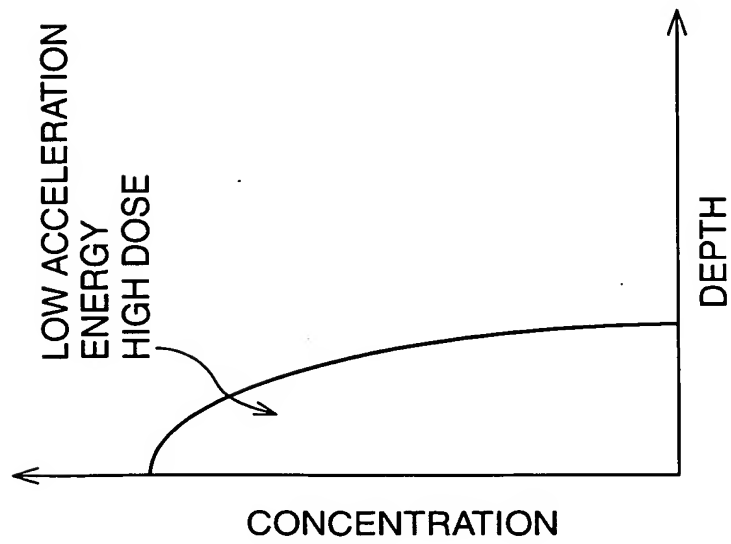
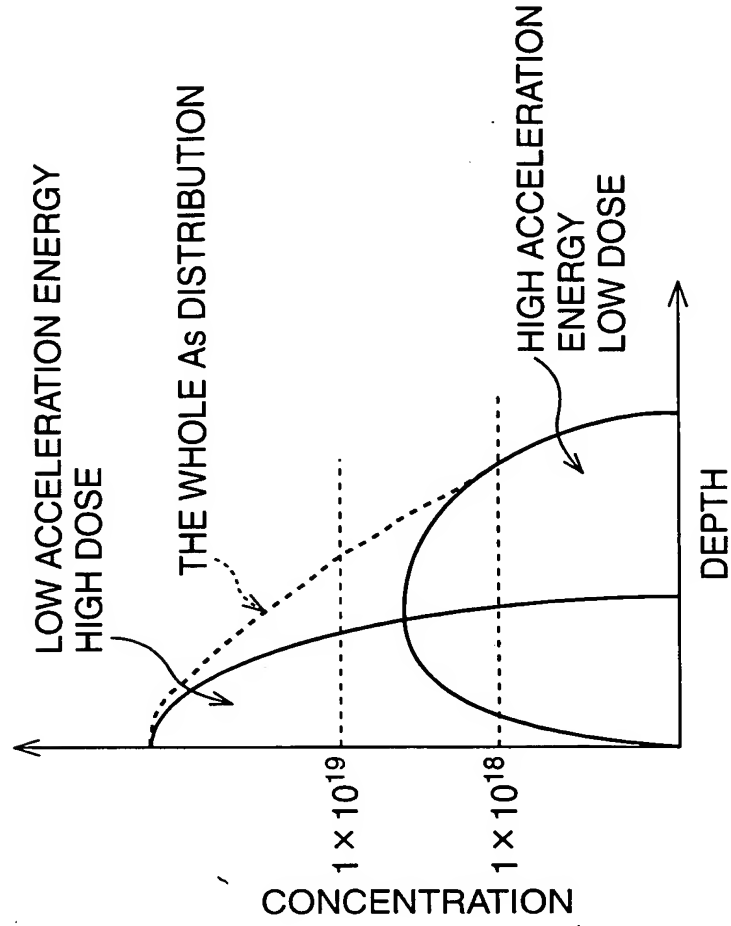


FIG. 1A



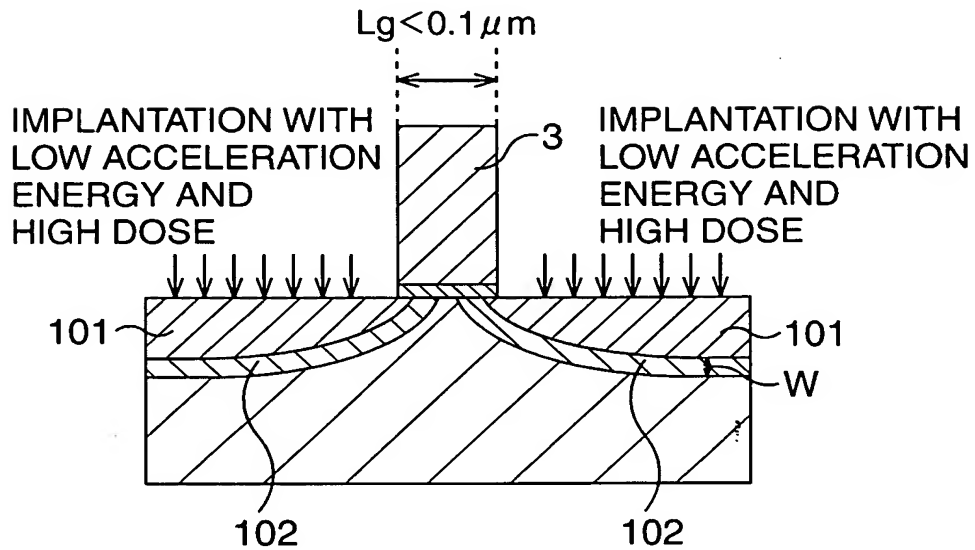
PRIOR ART
(SINGLE As⁺ IMPLANTATION)

FIG. 1B



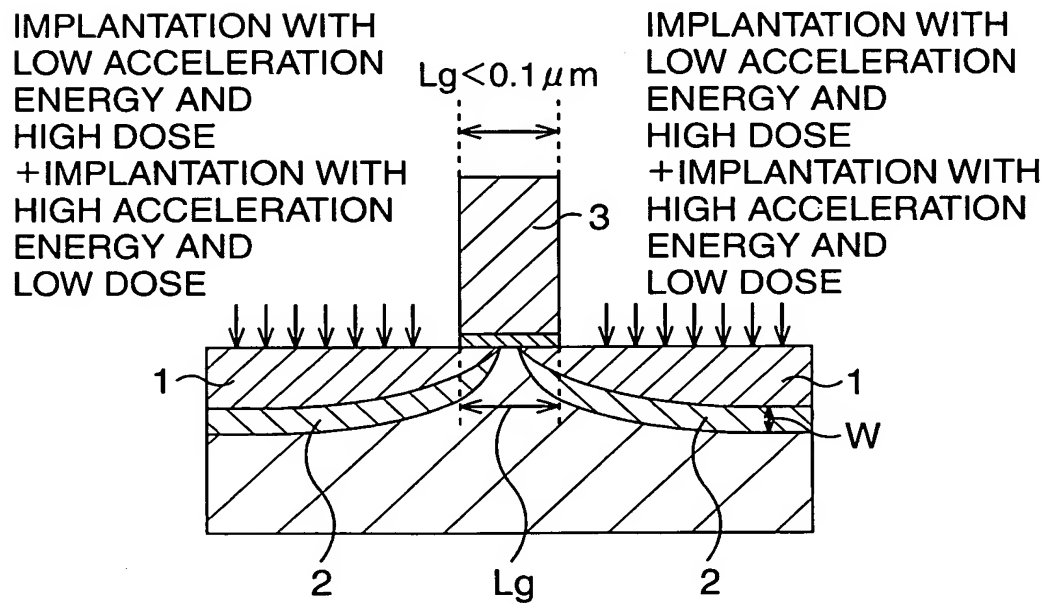
PRESENT INVENTION
(DOUBLE As⁺ IMPLANTATION)

FIG. 2A



PRIOR ART

FIG. 2B



PRESENT INVENTION

FIG. 3

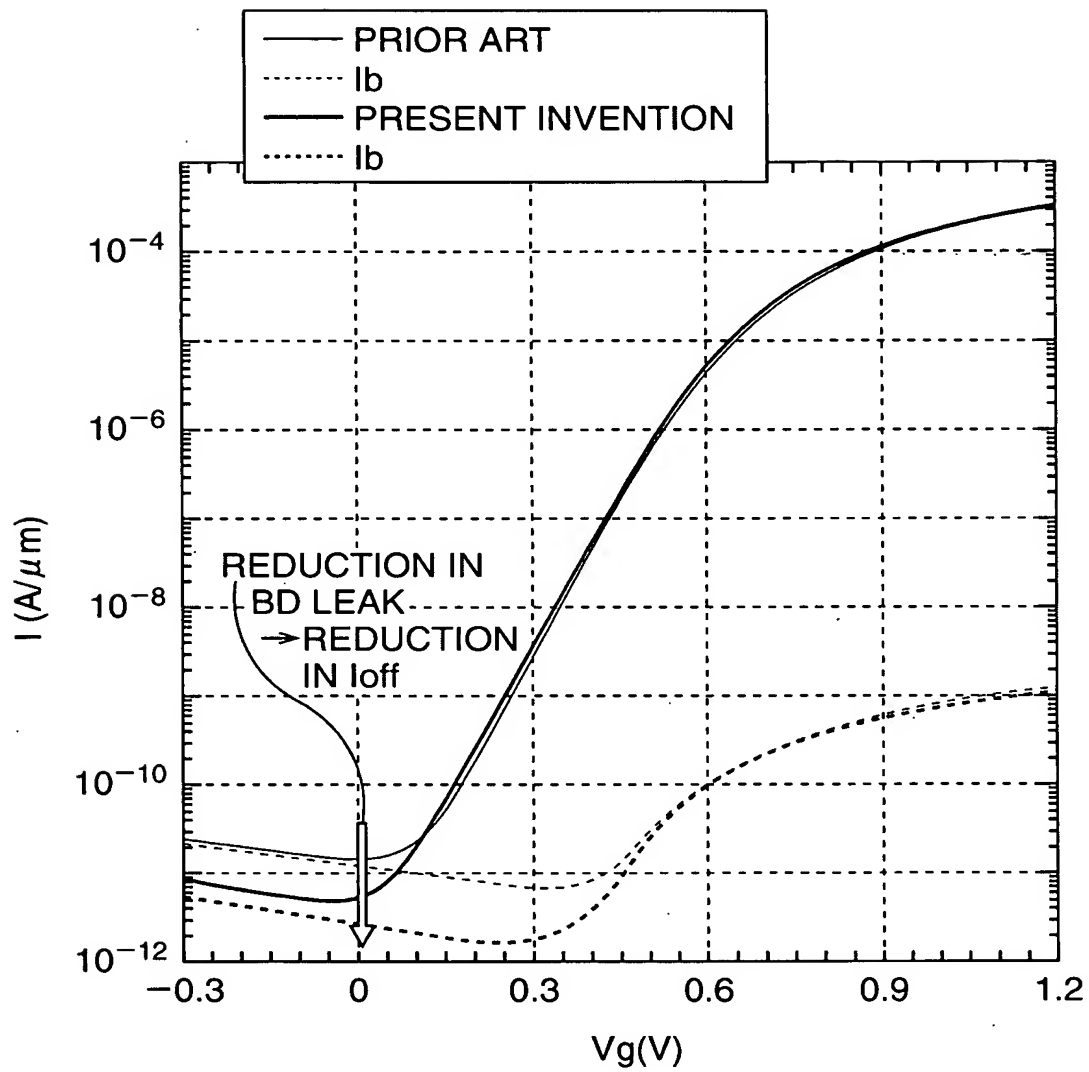


FIG. 4A

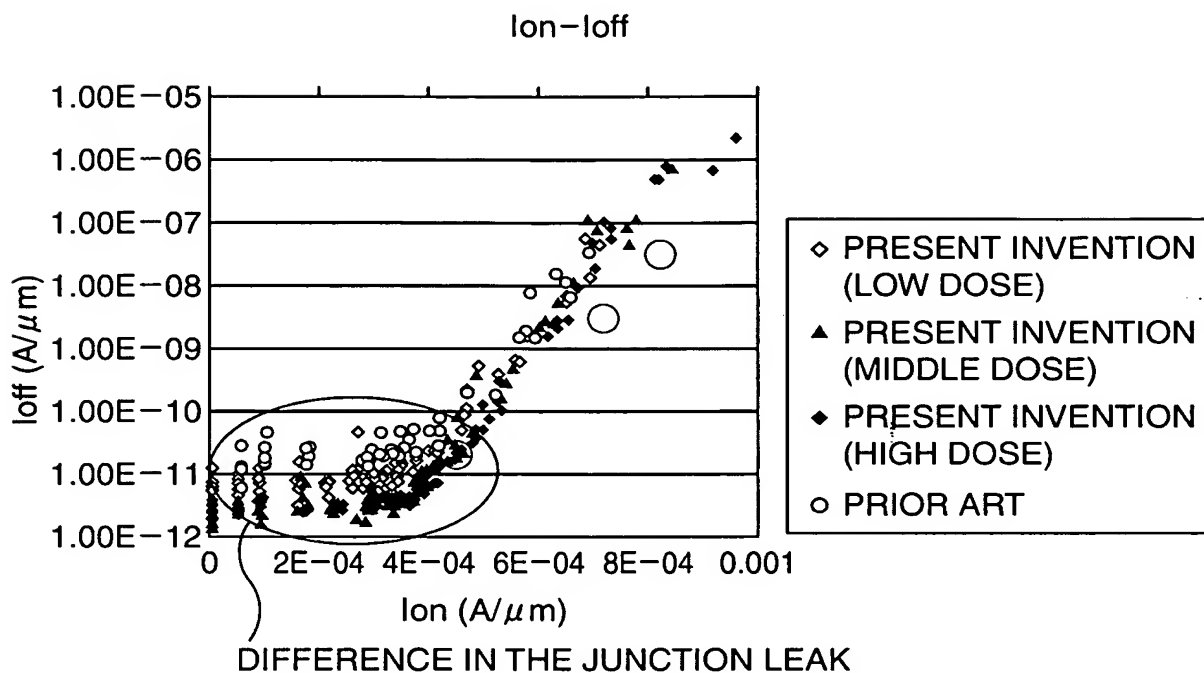


FIG. 4B

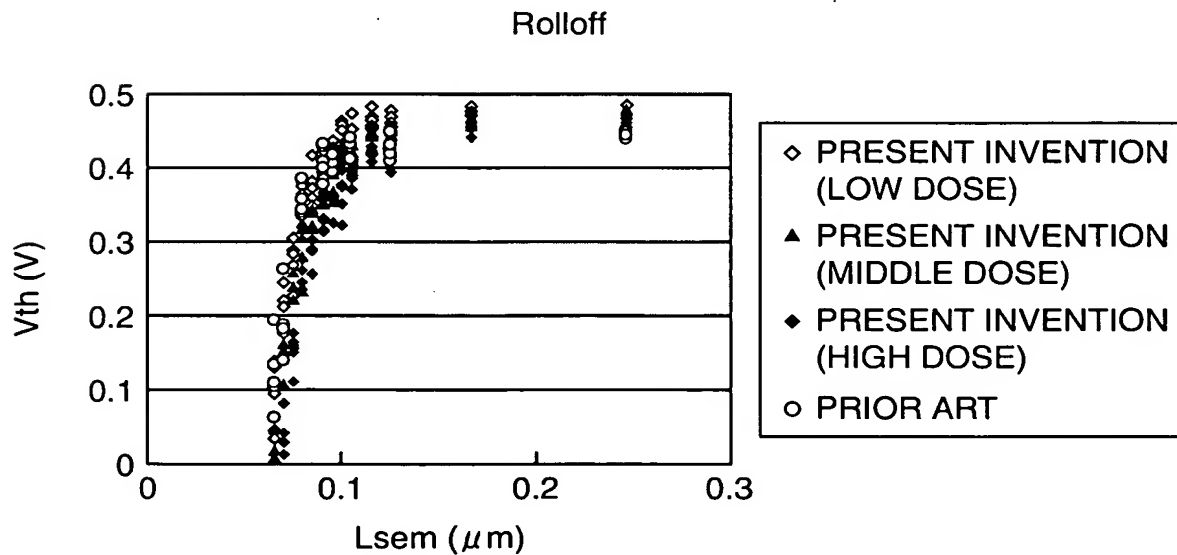
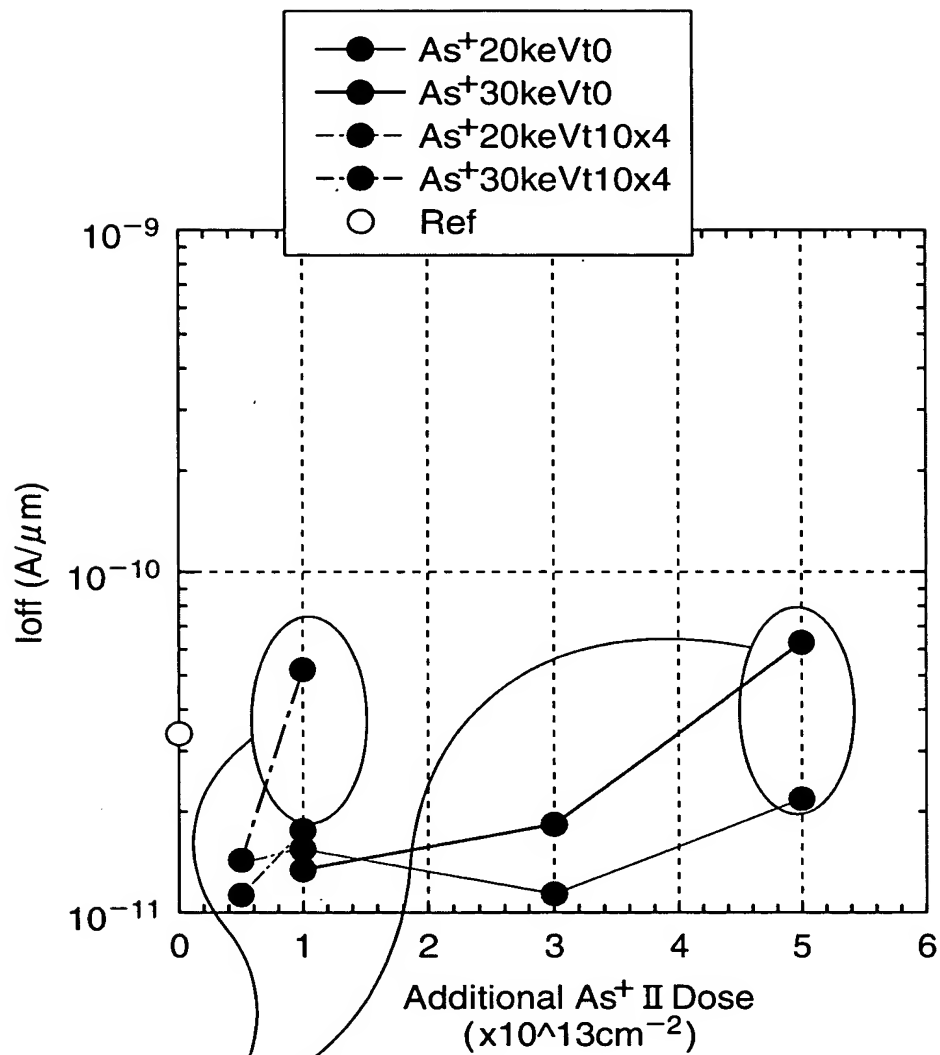
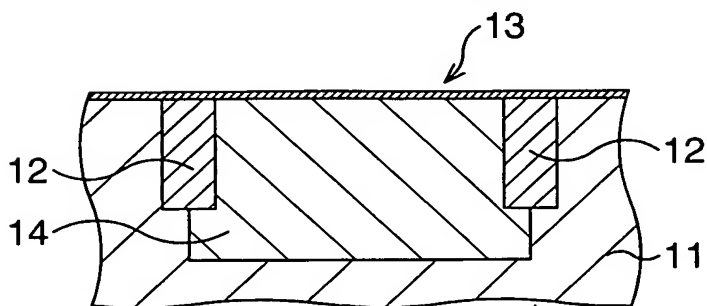


FIG. 5



INCREASE IN I_{off} DUE TO DEGRADATION IN ROLL-OFF CHARACTERISTIC
 $L_g = 80nm$
 $V_d = 1.2V$

FIG. 6A



Pwell - II (B^+)
 NVT - II (B^+)

FIG. 6B

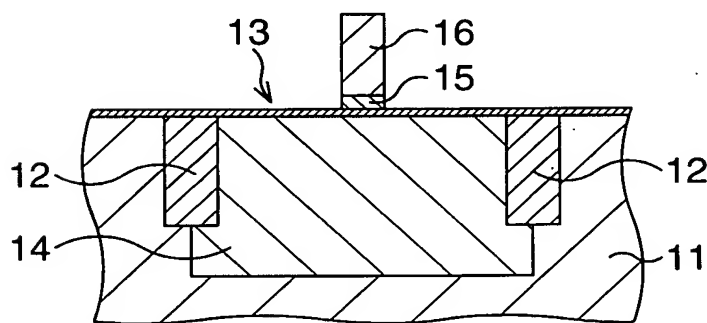


FIG. 6C

IMPLANTATION OF EXTENSION
 As^+ 20~30keV $1 \sim 3e13t0$
 $+As^+$ 0.5~5keV $0.5 \sim 2.5e15t0$
 (DOUBLE As^+ IMPLANTATION)

IMPLANTATION OF POCKET
 B^+ 5~7keV
 $6 \sim 15e12x4t28$

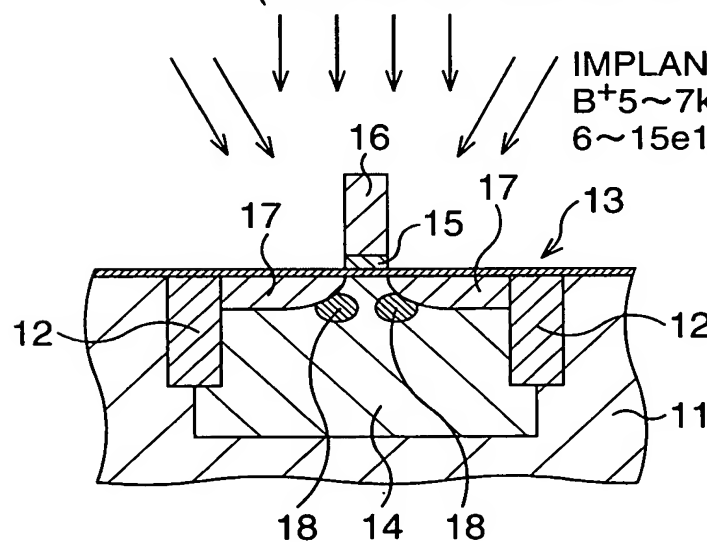


FIG. 7A

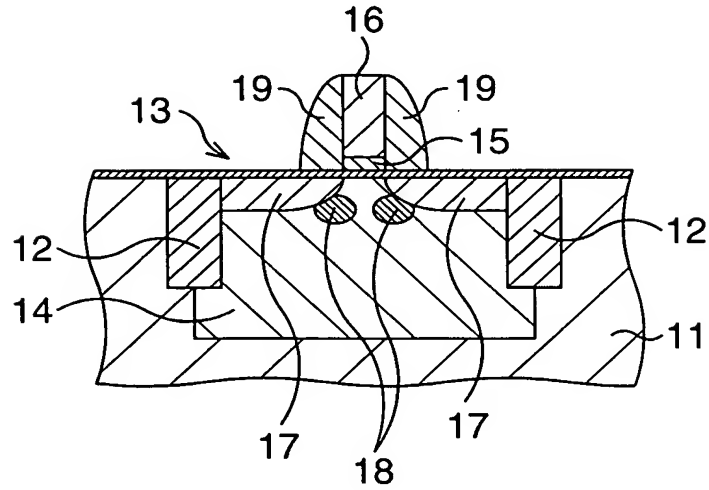


FIG. 7B

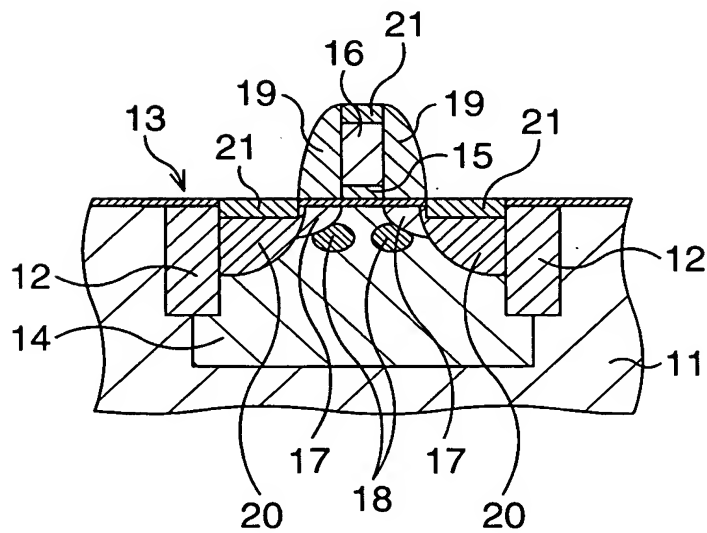


FIG. 8

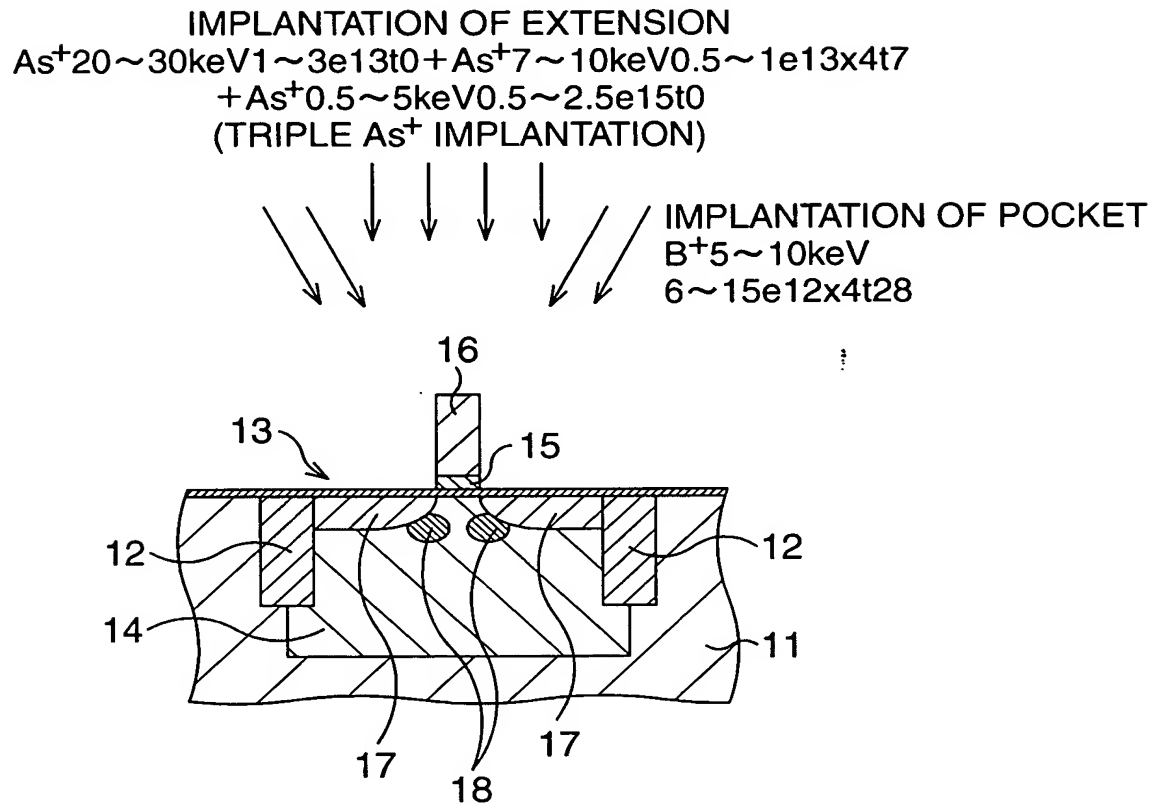
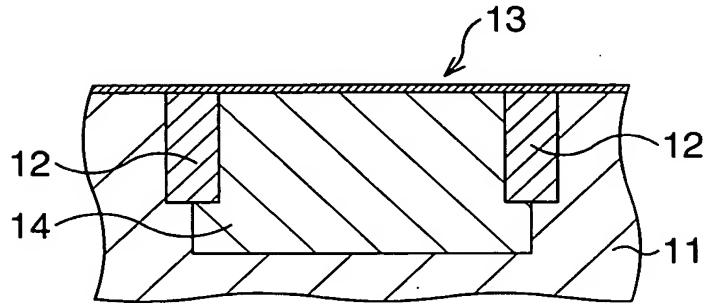


FIG. 9A



Pwell - II (B^+)
 NVT - II (B^+)

FIG. 9B

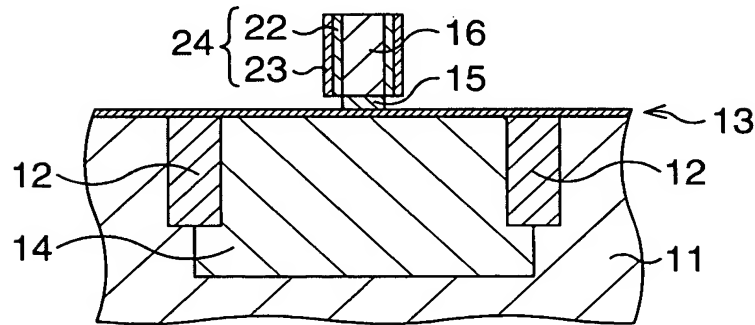
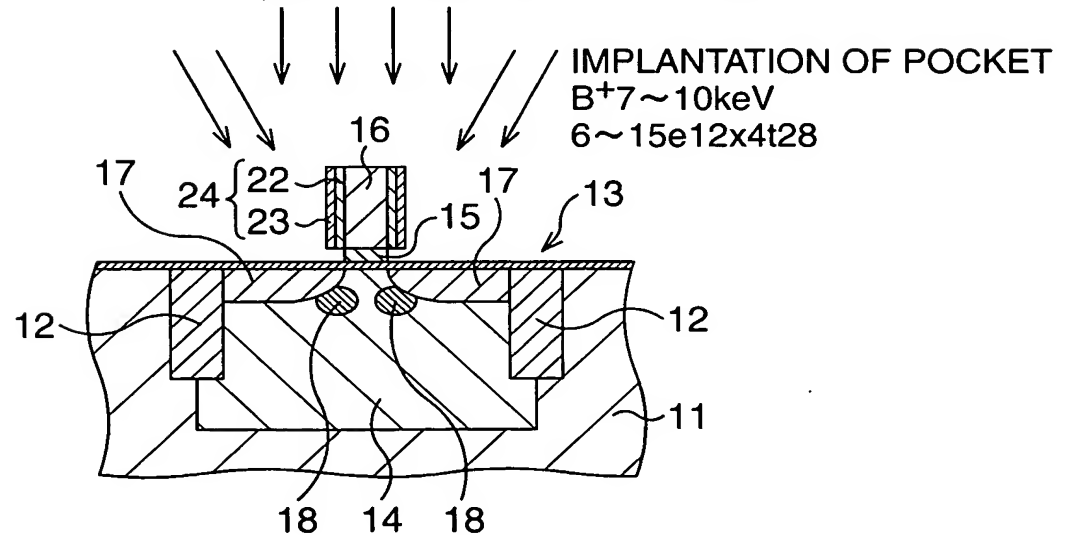


FIG. 9C

IMPLANTATION OF EXTENSION
 As^+ 20~30keV $1 \sim 3e13t0$
 $+ As^+$ 0.5~5keV $0.5 \sim 2.5e15t0$
 (DOUBLE As^+ IMPLANTATION)

IMPLANTATION OF POCKET
 B^+ 7~10keV
 $6 \sim 15e12x4t28$



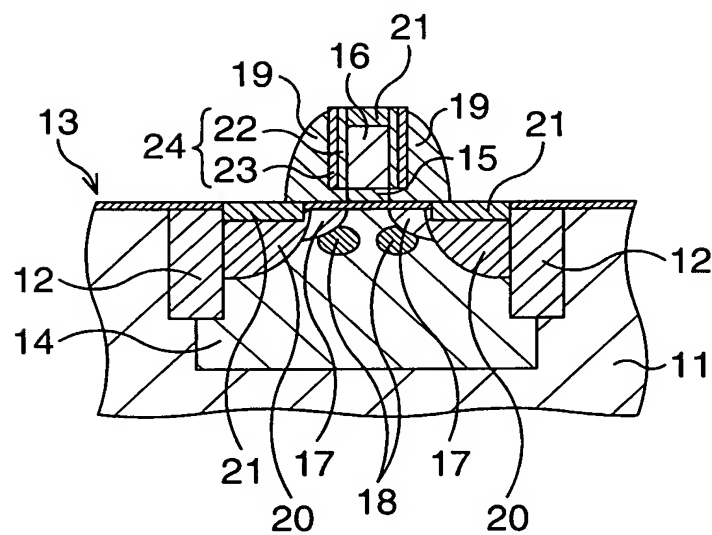
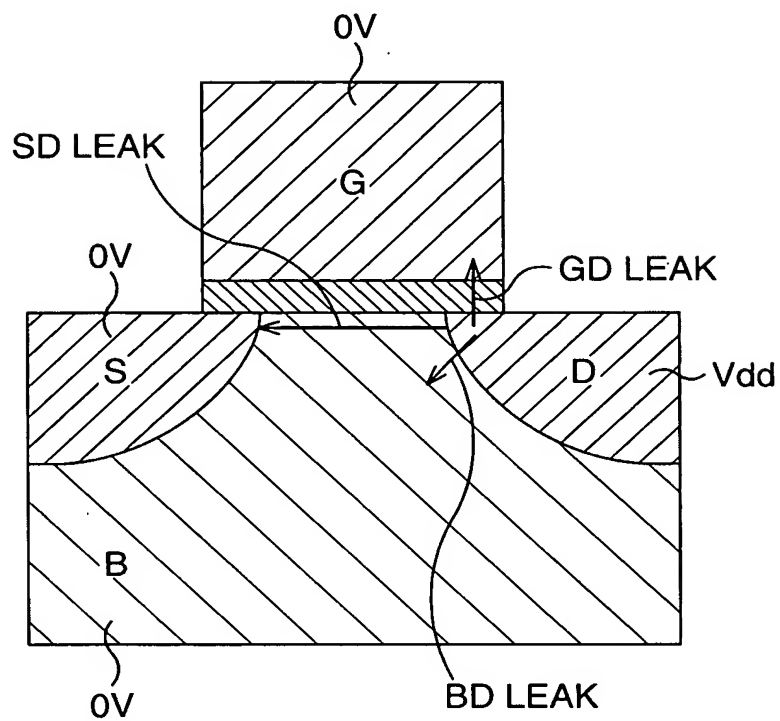


FIG. 11



$$I_{off} = \text{GD LEAK} + \text{SD LEAK} + \text{BD LEAK}$$

FIG. 12

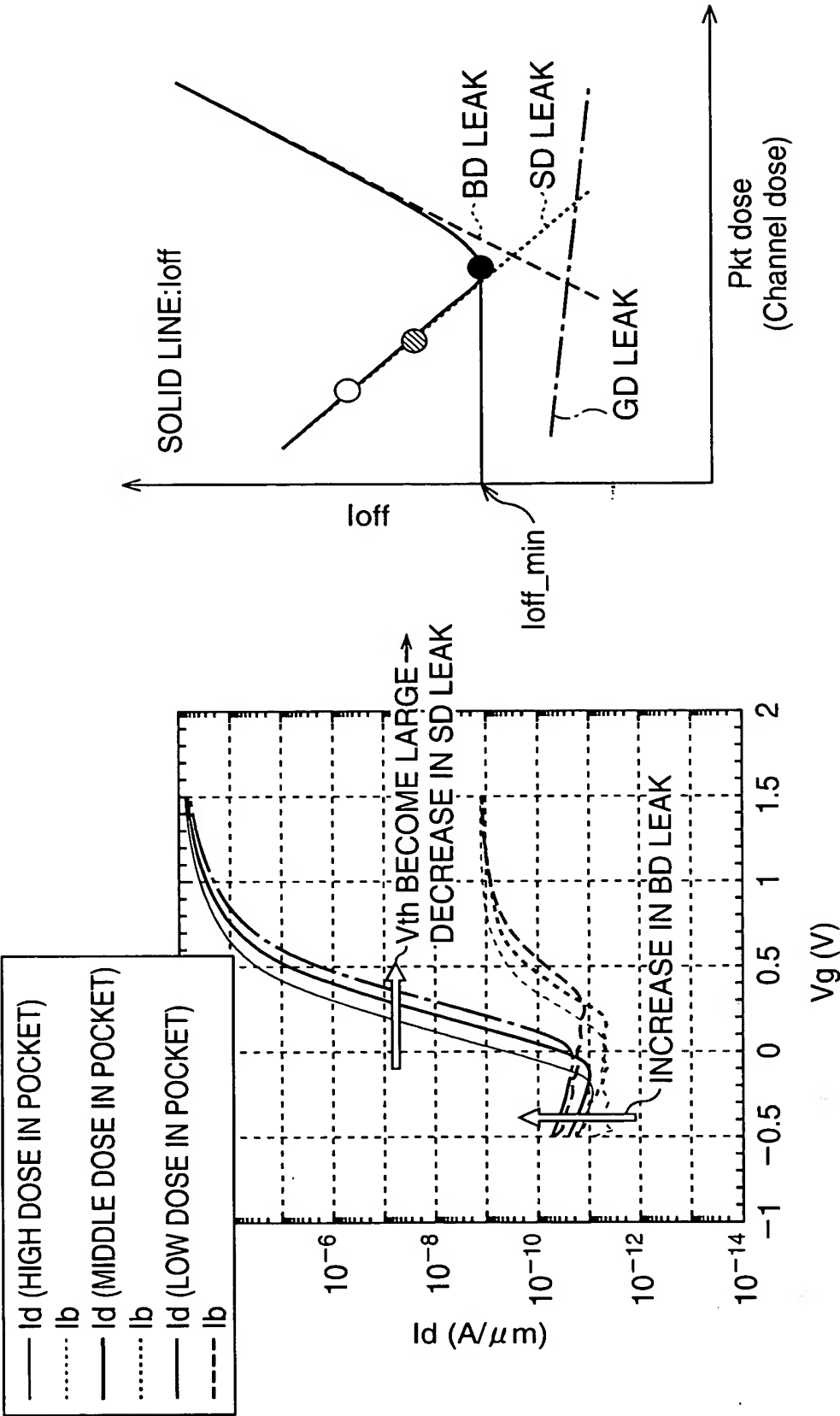


FIG. 13

